

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination ABE ET AL.	
		Examiner Jonathan G. Cwern	Art Unit 2809	Page 1 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,678,996 A	07-1987	Haacke et al.	324/309
*	B	US-4,740,749 A	04-1988	Yamamoto et al.	324/309
*	C	US-4,748,410 A	05-1988	Macovski, Albert	324/309
*	D	US-4,885,537 A	12-1989	Suzuki, Kazuo	324/309
*	E	US-5,311,132 A	05-1994	Noll et al.	324/309
*	F	US-5,348,011 A	09-1994	NessAiver, Moriel S.	600/411
*	G	US-5,713,358 A	02-1998	Mistretta et al.	600/420
*	H	US-5,830,143 A	11-1998	Mistretta et al.	600/420
*	I	US-5,897,496 A	04-1999	Watanabe, Shigeru	600/413
*	J	US-5,977,769 A	11-1999	Bornert et al.	324/306
*	K	US-5,987,348 A	11-1999	Fischer et al.	600/413
*	L	US-5,997,883 A	12-1999	Epstein et al.	324/306
*	M	US-6,068,595 A	05-2000	Miyazaki et al.	600/410

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/549,340	Applicant(s)/Patent Under Reexamination ABE ET AL.
	Examiner Jonathan G. Cwern	Art Unit 2809

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,121,775 A	09-2000	Pearlman, Justin D.	324/309
*	B	US-6,195,579 B1	02-2001	Carroll et al.	600/420
*	C	US-6,198,959 B1	03-2001	Wang, Yi	600/413
*	D	US-2002/0032376 A1	03-2002	Miyazaki et al.	600/410
*	E	US-6,381,486 B1	04-2002	Mistretta et al.	600/420
*	F	US-6,380,740 B1	04-2002	Laub, Gerhard	324/309
*	G	US-6,377,835 B1	04-2002	Schoenberg et al.	600/419
*	H	US-2002/0087068 A1	07-2002	Foo, Thomas K.F.	600/413
*	I	US-2002/0087069 A1	07-2002	Ho et al.	600/415
*	J	US-2002/0107438 A1	08-2002	Liu et al.	600/410
*	K	US-2003/0011368 A1	01-2003	Abe, Takayuki	324/309
*	L	US-2003/0032877 A1	02-2003	Watts et al.	600/410
*	M	US-2003/0060698 A1	03-2003	Mistretta, Charles A.	600/410

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/549,340	ABE ET AL.
	Examiner	Art Unit
	Jonathan G. Cwern	2809
		Page 3 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0071618 A1	04-2003	DiCarlo, Juile Camille	324/307
*	B	US-6,556,856 B1	04-2003	Mistretta et al.	600/420
*	C	US-2003/0080737 A1	05-2003	Loeffler, Ralf	324/307
*	D	US-6,580,937 B2	06-2003	Ho et al.	600/415
*	E	US-6,597,937 B2	07-2003	Liu et al.	600/420
*	F	US-2003/0135103 A1	07-2003	Mistretta, Charles A.	600/410
*	G	US-6,611,144 B2	08-2003	Abe, Takayuki	324/309
*	H	US-6,603,992 B1	08-2003	Debbins et al.	600/420
*	I	US-6,630,828 B1	10-2003	Mistretta et al.	324/309
*	J	US-6,639,211 B1	10-2003	Anand et al.	250/282
*	K	US-6,643,534 B2	11-2003	Foo et al.	600/420
*	L	US-6,653,834 B2	11-2003	Beck et al.	324/309
*	M	US-6,683,454 B2	01-2004	Rehwald et al.	324/307

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/549,340	ABE ET AL.	
	Examiner Jonathan G. Cwern	Art Unit 2809	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0027124 A1	02-2004	Abe et al.	324/306
*	B	US-2004/0061496 A1	04-2004	Ookawa, Masashi	324/307
*	C	US-6,745,064 B2	06-2004	Fuderer et al.	600/410
*	D	US-6,784,664 B2	08-2004	Liang et al.	324/309
*	E	US-6,801,800 B2	10-2004	Miyazaki et al.	600/410
*	F	US-2005/0033159 A1	02-2005	Mistretta et al.	600/420
*	G	US-2005/0058352 A1	03-2005	Deliwala, Shrenik	382/232
*	H	US-6,914,429 B2	07-2005	Ookawa, Masashi	324/309
*	I	US-2005/0203377 A1	09-2005	Watts et al.	600/410
*	J	US-2006/0183996 A1	08-2006	Abe et al.	600/410
*	K	US-2006/0232273 A1	10-2006	Takizawa et al.	324/309
*	L	US-7,167,740 B2	01-2007	Abe et al.	600/420
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.